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				Application Number	10/555,663-Conf. #9919
				Filing Date	December 4, 2006
				First Named Inventor	Shigenori FUJIKAWA
				Art Unit	4191
				Examiner Name	B. A. Schiffman
Sheet	1	of	1	Attorney Docket Number	1248-1030PUS1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
	AA*	US-20020182413-A1	12-05-2002	Kunitake et al.	
	AB*	US-5,284,707-A	02-08-1994	Ogawa et al.	
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	AL*	US-2002/0127331-A1	09-12-2002	Ogawa et al.	
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	AN*	US-2002/0088540-A1	07-11-2002	Chan et al.	
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
	BA	JP-10-146920-A	06-02-1998			AB
	BB	JP-2002-337100-A	11-26-2002			AB
	BC	JP-2003-124250-A	04-25-2003			AB
	BD	JP-10-249985-A	09-22-1998	Kunitake et al.		√
Examiner Signature				Date Considered		

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	CA	H. FUJII et al., "Synthesis of TiO ₂ /CdS nanocomposite via TiO ₂ coating on CdS nanoparticles by compartmentalized hydrolysis of Ti alkoxide", Journal of Materials Science, Vol. 36, pp. 527-532 (2001)	
	CB	B.E. YOLDAS, "Deposition and properties of optical oxide coatings from polymerized solutions", Applied Optics, Vol. 21, No. 16, pp. 2960-2964, August 15, 1982	

Examiner Signature	/Benjamin Schiffman/	Date Considered	11/19/2009
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